

Product Description

DELIVERY TERM IS WITHIN 6 MONTHS!

High Resolution High Accuracy AFM Cantilevers HA_NC series are designed for Semiconduct (Intermittent), Noncontact applications. Each probe has 2 rectangular cantilevers. Typical Resonant Frequency 235kHz / 140kHz (dispersion $\pm 10\%$). Typical Force Constant 12N/m / 3.5N/m (dispersion $\pm 20\%$). Cantilever has Au reflective side coating to increase laser signal. Probes are also available with no coating as well as with conductive tip coating.

Probes are packed in boxes with 15 and 50 pieces. Amount discount is included in the package price.

High Accuracy composite ETALON probes combine the main features allowing to obtain high quality AFM images:

- Sharp tip - curvature radius < 10 nm.
- Resonance frequency, specified with high accuracy - $\pm 10\%$ within a wafer.
- Special chip geometry with vertical sidewalls for convenient operating.
- High aspect ratio tip.
- Enhanced back-side reflection of the cantilever.
- Cost effective price.

General Features

Material	Polysilicon cantilever, silicon tip
Chip size	3.6x1.6x0.4mm
Reflective side coating	Au
Tip coating	No
Tip curvature radius	< 10nm
Available tip coatings	Pt, Au, W2C

Special Features

Cantilever series	Cantilever	Cantilever length, L $\pm 2\mu\text{m}$	Cantilever width, W $\pm 3\mu\text{m}$	Cantilever thickness, T $\pm 0.15\mu\text{m}$	Resonant frequency, kHz			Force constant, N/m		
					min	typical	max	min	typical	max
HA_NC	A	94	34	1.85	210	235	260	9	12	15
	B	124	34	1.85	125	140	155	2.5	3.5	4.5